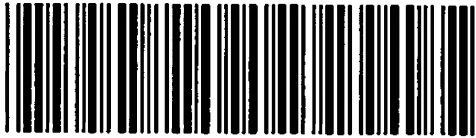


**Search Notes**

Application/Control No.

10/722,186

Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

KAMASAKI ET AL.

Art Unit

2174

**SEARCHED**

Class	Subclass	Date	Examiner
715	773	4/15/2007	LEE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	as above	4/15/2007	LEE

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search attached	4/15/2007	LEE